

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination BAKKERS ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Different behavior of photoluminescence anisotropy in porous silicon layers made by polarized-light-assisted electrochemical etching" Hideki Koyama, Applied Physics Letters Vol. 80, number 6, 11 February 2002. Pages 965-967.
	V	"Fabrication of Metal Nanowires Using Microcontact Printing" Matthias Geissler et al. 2003 American Chemical Society Langmuir 2003, 19, 6301-6311.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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